

March 2011
SupreMOS®

# FCA36N60NF

# N-Channel SupreMOS<sup>®</sup>, FRFET<sup>®</sup>,MOSFET 600V, 36A, 95m $\Omega$

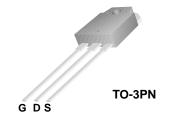
#### **Features**

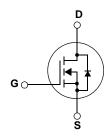
- $R_{DS(on)} = 80 m\Omega$  ( Typ.)@  $V_{GS} = 10 V$ ,  $I_D = 18 A$
- Ultra Low Gate Charge (Typ. Qg = 86nC)
- Low Effective Output Capacitance
- 100% Avalanche Tested
- · RoHS Compliant

# **Description**

The SupreMOS® MOSFET, Fairchild's next generation of high voltage super-junction MOSFETs, employs a deep trench filling process that differentiates it from preceding multi-epi based technologies. By utilizing this advanced technology and precise process control, SupreMOS® provides world class Rsp, superior switching performance and ruggedness.

This SupreMOS® MOSFET fits the industry's AC-DC SMPS requirements for PFC, server/telecom power, FPD TV power, ATX power, and industrial power applications.





# MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted\*

Symbol		Parameter		FCA36N60NF	Units
V <sub>DSS</sub>	Drain to Source Voltage			600	V
V <sub>GSS</sub>	Gate to Source Voltage			±30	V
1	Drain Current	Continuous (T <sub>C</sub> = 25°C)		34.9	Α
Drain Current	Continuous (T <sub>C</sub> = 100°C)		22	А	
I <sub>DM</sub>	Drain Current	Pulsed (N	104.7	Α	
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		1800	mJ	
I <sub>AR</sub>	Avalanche Current		12	Α	
E <sub>AR</sub>	Repetitive Avalanche Energy			3.12	mJ
dv/dt	Peak Diode Recovery dv/dt		ote 3)	50	V/ns
uv/ul	MOSFET dv/dt Ruggedness			100	V/115
P <sub>D</sub> Po	Power Dissipation	$(T_C = 25^{\circ}C)$		312	W
	Power Dissipation	Derate above 25°C		2.6	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range			-55 to +150	°C
T <sub>L</sub>	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	°C

<sup>\*</sup>Drain current limited by maximum junction temperature

### **Thermal Characteristics**

Symbol	Parameter	FCA36N60NF	Units	
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.40		
$R_{\theta CS}$	Thermal Resistance, Case to Heat Sink (Typical)	0.24		
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	40		

Units

Max.

# Package Marking and Ordering Information $T_C = 25^{\circ}C$ unless otherwise noted

Parameter

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FCA36N60NF	FCA36N60NF	TO-3PN	-	-	30

**Test Conditions** 

Min.

Typ.

# **Electrical Characteristics**

Off Chara	Off Characteristics					
$BV_DSS$	Drain to Source Breakdown Voltage	$I_D = 1 \text{mA}, V_{GS} = 0 \text{V}, T_J = 25 ^{\circ} \text{C}$	600	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 1mA, Referenced to 25°C	-	0.60	-	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 480V, V <sub>GS</sub> = 0V	-	-	10	μА
-DSS	$T_{J} = 125^{\circ}C$	-	-	100	μ, τ	
$I_{GSS}$	Gate to Body Leakage Current	$V_{GS} = \pm 30V, V_{DS} = 0V$	-	-	±100	nA

#### **On Characteristics**

Symbol

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	3.0	3.7	5.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 18A$	-	80	95	mΩ
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 20V, I_{D} = 18A$	-	39	-	S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 400V V 0V	-	3191	4245	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 100V, V_{GS} = 0V$ f = 1MHz		145	195	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 = 1141112	-	5	8	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 380V, V_{GS} = 0V, f = 1MHz$	-	81	-	pF
C <sub>oss</sub> eff.	Effective Output Capacitance	$V_{DS} = 0V$ to 480V, $V_{GS} = 0V$	-	338	-	pF
$Q_{g(tot)}$	Total Gate Charge at 10V $V_{DS} = 380V$ , $I_D = 18A$ ,		-	86	112	nC
$Q_{gs}$	Gate to Source Gate Charge	V <sub>GS</sub> = 10V	-	16	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	(Note 4)	-	36	-	nC
ESR	Equivalent Series Resistance (G-S)	Drain Open, f=1MHz	-	1.2	-	Ω

### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		-	27	64	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 380V, I_D = 18A$	-	17	44	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 4.7\Omega$	-	92	194	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)	-	4	18	ns

#### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current			-	36	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	108	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 18A	-	-	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 18A	-	166	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	-	1.3	-	μС

#### Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. I $_{AS}$  = 12A, R $_{G}$  = 25 $\Omega$ , Starting T $_{J}$  = 25 $^{\circ}$ C
- 3.  $I_{SD} \leq$  36A, di/dt  $\leq$  1200A/ $\mu$ s,  $V_{DD} \leq$  380V, Starting  $T_J$  = 25°C
- 4. Essentially Independent of Operating Temperature Typical Characteristics

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

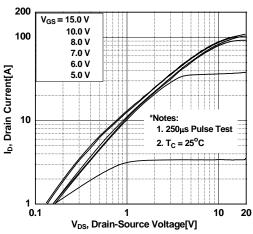


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

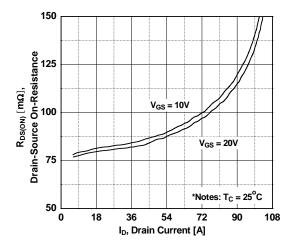


Figure 5. Capacitance Characteristics

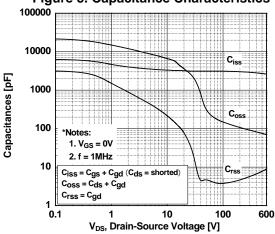


Figure 2. Transfer Characteristics

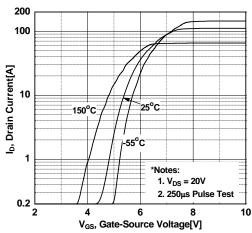


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

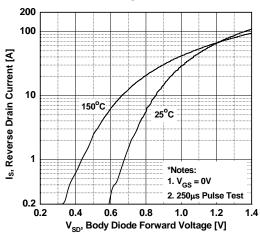
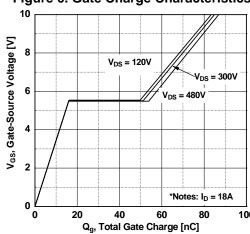


Figure 6. Gate Charge Characteristics



# **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

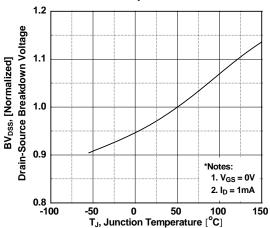


Figure 8. On-Resistance Variation vs. Temperature

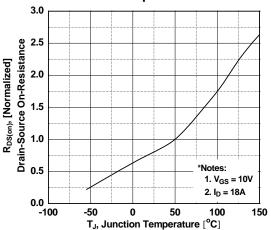


Figure 9. Maximum Safe Operating Area

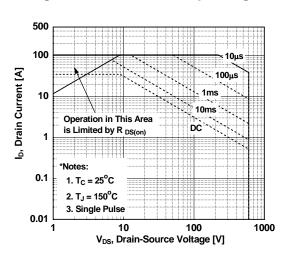


Figure 10. Maximum Drain Current vs. Case Temperature

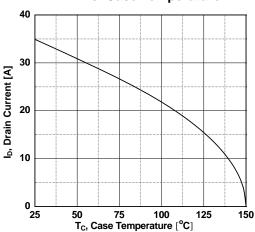
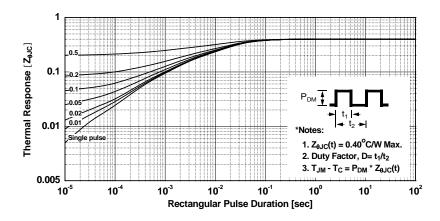
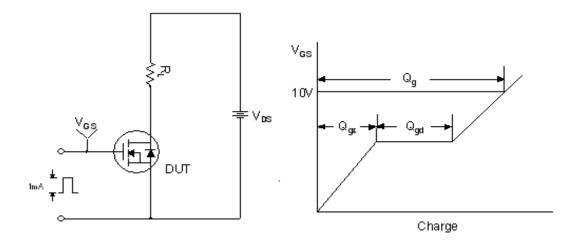


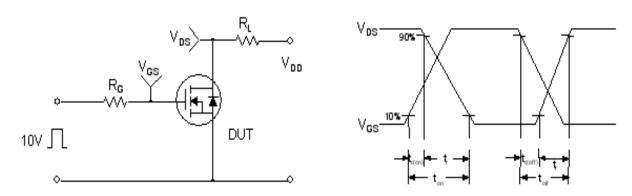
Figure 11. Transient Thermal Response Curve



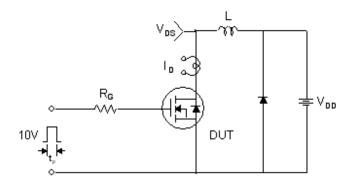
#### **Gate Charge Test Circuit & Waveform**

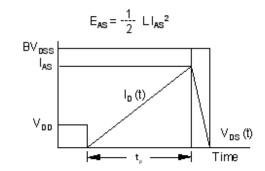


#### **Resistive Switching Test Circuit & Waveforms**

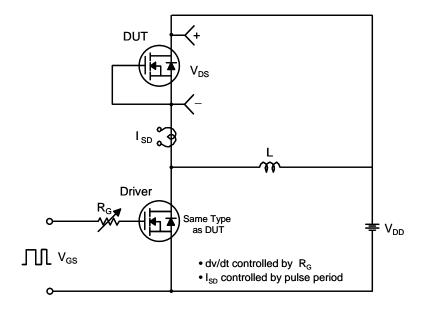


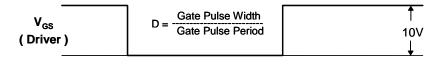
#### **Unclamped Inductive Switching Test Circuit & Waveforms**

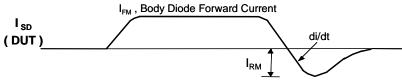




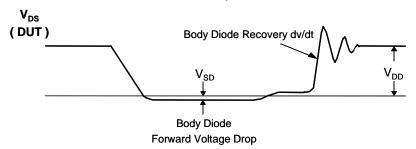
#### Peak Diode Recovery dv/dt Test Circuit & Waveforms





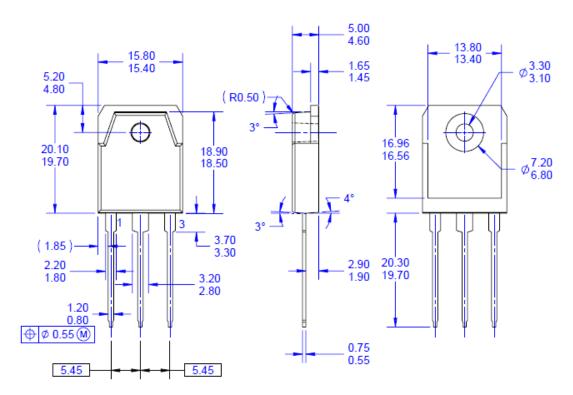


Body Diode Reverse Current



# **Mechanical Dimensions**

# TO-3PN



# (R0.50) m

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